


<b>Search Notes</b>  	<b>Application/Control No.</b>  10076367	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Mills, Donald L	<b>Art Unit</b>  2462

SEARCHED			
Class	Subclass	Date	Examiner
370	230,230.1,235,236.2,298,401,412,428,429,465	6/14/2006	DLM
Above Updated		9/30/2006	DLM
Above Updated		8/17/2007	DLM
Above Updated		12/20/2007	DLM
Above Updated		10/26/2008	DLM
Above Updated		5/21/2009	DLM
Above Updated		12/19/2009	DLM

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US PGPUBS, US PATS, EPO, JPO, IBM, DERWENT)	6/15/2006	DLM
IEEE - <a href="http://ieee.ieeeexplore.org">ieee.ieeeexplore.org</a> - packet filtering	6/15/2006	DLM
Internet - <a href="http://google.com">google.com</a> - packet filtering	6/15/2006	DLM
Above Updated	9/30/2006	DLM
Above Updated	8/17/2007	DLM
Above Updated	12/20/2007	DLM
Above Updated	10/26/2008	DLM
Above Updated	5/21/2009	DLM
Above Updated	12/19/2009	DLM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
See Interference Search History Printout		12/19/2009	DLM

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